

MTEK Series - Legacy ATE System Upgrade Kit

Keysight Technologies and
Marvin Test Solutions

Easily extend the life of your legacy semiconductor ATE with this low-cost, PXI-based, add-on solution

Solve your semiconductor ATE system obsolescence problem

Simply testing today's advanced semiconductor devices with yesterday's ATE is not an option. With each new development in device technology, the test requirements can outpace the capabilities of the available test equipment. Marvin Test Solutions' cost-effective, Marvin Test Expansion Kit (MTEK) platform provides the solution.

The MTEK platform breathes new life into your legacy semiconductor test systems with a PXI-based, add-on solution that easily adds capability without the expense of replacing the entire test system.

Part of Marvin Test Solutions' suite of semiconductor test solutions, ideal for engineering and production applications as well as incoming inspection and failure analysis, the MTEK Series is a flexible, scalable, test system upgrade for both wafer and packaged test.

Combining Marvin Test Solutions' MTEK with Keysight Technologies' RF instrumentation, you can add the capabilities to address a wide range of RF and mixed-signal device testing requirements for both wafer and packaged test. The MTEK's open architecture can accommodate the full range of Keysight's RF PXI products, including vector signal generators, vector signal analyzers, and vector network analyzers, Marvin Test Solutions' extensive line of digital test products, as well as additional baseband instrumentation.

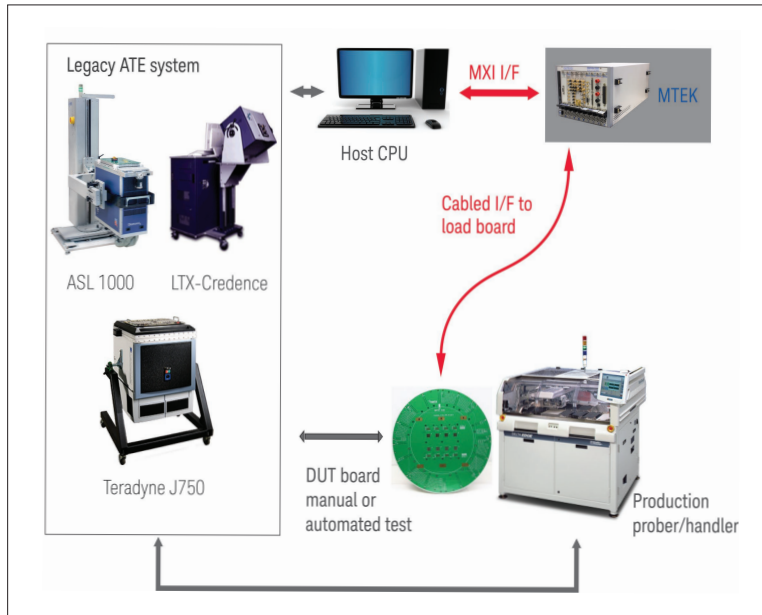


- Upgrade for legacy semiconductor test systems including Teradyne, LTX/Credence, and Verigy platforms
- Cost-effective PXI-based, add-on solution with an open architecture
- Easily add RF, digital, and analog performance
- Add the performance you need with Keysight's wide selection of RF instruments
- Fast implementation; the PXI chassis becomes an extension of the host CPU
- Simplified integration with existing test programs via DLL calls to the new instruments
- Easy integration with test floor data collection, data analysis, etc.
- Reduce time spent on training; little or no additional training for production personnel
- Multisite capability for both wafer sort and packaged test

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The MTEK platform offers a you cost-effective, performance solution that addresses common legacy test system challenges:

- Existing test systems are 20+ years old, with dated and limited capacities
- New test capabilities for testing and characterizing new designs
- Costs of new tests systems are prohibitive
- New test systems require learning new tools



System Components

Keysight Technologies

M938x/M942x	PXI Vector Signal Generators
M9290A	PXIe Vector Signal Analyzer
M937x	PXIe Vector Network Analyzers

Marvin Test Solutions

MTEK Series	Marvin Test Expansion Kit
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To learn how this solution can address your specific needs please contact Keysight's solutions partner, Marvin Test Solutions www.keysight.com/find/marvin



Keysight & Solutions Partners
Extending our solutions to meet your needs

Keysight and its Solutions Partners work together to help customers meet their unique challenges, in design, manufacturing, installation or support. To learn more about the program, our partners and solutions go to www.keysight.com/find/solutionspartner

Marvin Test Solutions, designs and delivers innovative, feature-rich solutions for the world's leading military, aerospace, and manufacturing organizations. www.marvintest.com

For information on Keysight Technologies' products, applications and services, go to www.keysight.com

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